

Notice of References Cited	Application/Control No. 10/662,287	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0227458 A1	11-2004	He et al.	313/504
	B	US-2004/0189167 A1	09-2004	Adachi et al.	313/501
	C	US-2004/0051445 A1	03-2004	Adachi, Masaya	313/504
	D	US-2002/0079831 A1	06-2002	He et al.	313/504
	E	US-6,710,541 B2	03-2004	He et al.	313/504
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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